(BX)
int(s)
CHY, KRISTOPHER J.
1
dence address If not included ailed in due course. THIS val from issue at the initiat
tage application from the g with the requirements DMENT or NOTICE OF ficient. Ched on of front (not the back) of
submitted. Note the RIAL.
olication (PTO-152) 3), 5 . nment asons for Allowance
3), <u>5</u> . nm

Application/Control Number: 10/748,344

Art Unit: 2823

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Michael A. Bernadicou (Reg. No. 35,934) on 19 December 2005.

The application has been amended as follows:

a) In the Claims

In claim 38, line 8, before "induce", insert --preferentially--

in lines 10 - 12, after "induce" delete "heating in the semiconductor die; and heating the semiconductor die to couple the semiconductor die with the next level package" and insert --eddy currents in the semiconductor die to heat the semiconductor die and couple the semiconductor die with the next level package--

In claim 39, line 2, delete "semiconductor die" and insert --at least one interconnect--

In claim 41, line 11, before "induce" insert --preferentially--

in lines 10 - 12, delete "; and heating the semiconductor die to couple the semiconductor die with the next level package" and insert --to heat the semiconductor die and couple the semiconductor die with the next level package--

In claim 43, line 2, delete "semiconductor die" and insert -- at least one interconnect--

Application/Control Number: 10/748,344

Art Unit: 2823

In claim 44, line 9 before "induce" insert --preferentially--

in lines 9-11, delete "; and heating the at least one interconnect to couple the semiconductor die with the next level package" and insert --to heat the at least one interconnect and couple the semiconductor die with the next level package--

In claim 45, line 2, delete "at least one interconnect" and insert --semiconductor die--

In claim 47, line 11 before "induce" insert --preferentially--

in lines 11-13, delete "; and heating the at least one interconnect to couple the semiconductor die with the next level package" and insert --to heat the at least one interconnect and couple the semiconductor die with the next level package--

In claim 49, line 2, delete "at least one interconnect" and insert -- semiconductor die--

Reasons for Allowances

The following is an examiner's statement of reasons for allowance: while Grabbe, US Patent No. 5,816,482 teaches in fig. 4, col. 3, lines 15-54, the preferentially inducing eddy currents in the at least one interconnect on top of a substrate, but not an interconnect between a semiconductor die and a next level package, it does not teach the features in claim 1, lines, lines 7-10, "generating an electromagnetic flux with an inductor; and exposing the semiconductor die to the electromagnetic flux to preferentially induce eddy-currents in the semiconductor die to heat the semiconductor die and couple the semiconductor die with the next level package." While Tsumura, US

Application/Control Number: 10/748,344

Art Unit: 2823

414 14 0000

Patent No. 6,288,376 teaches the horizontal moving of the inductor across the work piece, the applicant has discounted this from his definition of scanning, on p. 13, ¶ 4 of Remarks received 14 November 2005, "It is Applicant's understanding that moving an induction heating coil horizontally is not equivalent to scanning an inductor around a semiconductor die to induce eddy currents in a semiconductor die or an interconnect." Based on this definition, Tsumura does not teach the features in claim 41, lines 8-13, "generating an electromagnetic flux with an inductor; scanning the inductor around the semiconductor die while generating an electromagnetic flux; exposing the semiconductor die to the electromagnetic flux to induce heating in the semiconductor die; and heating the semiconductor die to couple the semiconductor die with the next level package." The prior art of record fails to teach, in combination, the process features.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to William M. Brewster whose telephone number is 571-272-1854. The examiner can normally be reached on Full Time.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith can be reached on 571-272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Page 5

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

20 December 2005

William M. Brownts

WB